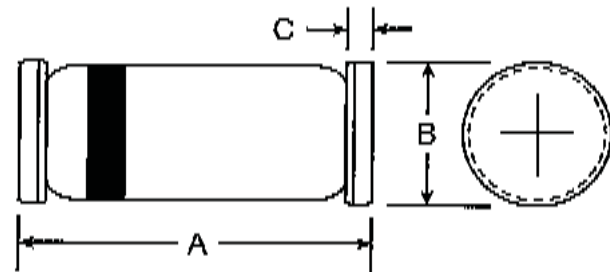


FEATURES

- Voltage range 100 Volts
- Surge overload ratings to 2 amperes peak
- Ideal for printed circuit board
- Reliable low cost construction utilizing molded plastic technique results in inexpensive product
- Terminal : Pure tin plated lead free,
- Mounting position: Any

MECHANICAL DATA

- Case: Mini MELF
- Terminals: Solderable per MIL-STD-202, Method 208
- Polarity: Cathode Band
- Marking: Cathode Band Only
- Weight: 0.05 grams (approx)



MINI-MELF		
Dim	Min	Max
A	3.30	3.70
B	1.30	1.60
C	0.28	0.50
All Dimensions in mm		

MINI-MELF(LL-34)
Dimensions in inches and (millimeters)

MAXIMUM RATINGS & ELECTRICAL CHARACTERISTICS

Rating at 25°C ambient temperature unless otherwise specified. Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%

Parameter	Symbol	LL4148	Unit
Maximum Repetitive Peak Reverse Voltage	V_{RRM}	100	V
Maximum RMS Voltage	V_{RMS}	75	V
Forward Repetitive Peak Current (Note 1)	I_{FSM}	500	mA
Forward DC current at $T_a=25^{\circ}C$	I_F	200	mA
Maximum Average Forward Current	$I_{F(AV)}$	150	mA
Peak Forward Surge Current $t_p=1\mu s$	I_{FSM}	2.0	A
Typical Resistance Junction to Ambient Air (Note 1)	$R_{\theta JA}$	350	K/W
Operating and Storage Temperature Range	T_J, T_{STG}	-65 to +175	$^{\circ}C$

Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Forward Voltage $I_F=5.0mA$ $I_F=50mA$	V_F	0.62	0.72 1.00	V
Peak Reverse Current $V_R=20V$ $V_R=20V, T_J=150^{\circ}C$ $V_R=75V$	I_R	—	25 50 5.0	nA uA uA
Reverse Recovery Time (Note 2)	t_{rr}	—	4.0	nS

NOTE: 1. Valid Provided that Terminals are Kept at Ambient Temperature.

2. Reverse Recovery Test Conditions: $I_F=10mA, V_R=6V, I_{rr}=0.1 \times I_R, R_L=100\Omega$

RATING & CHARACTERISTIC CURVES

FIG.1-MAXIMUM NON-REPETITIVE FORWARD SURGE CURRENT

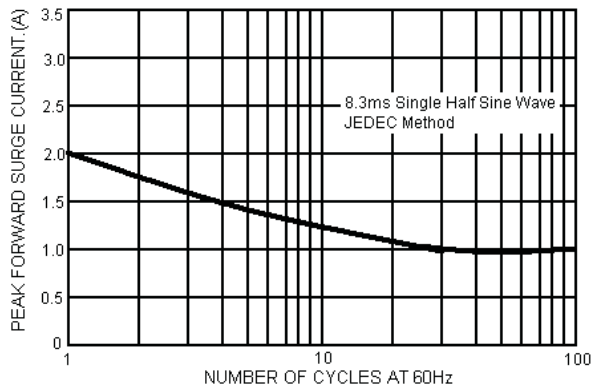


FIG.2-MAXIMUM FORWARD CURRENT DERATING

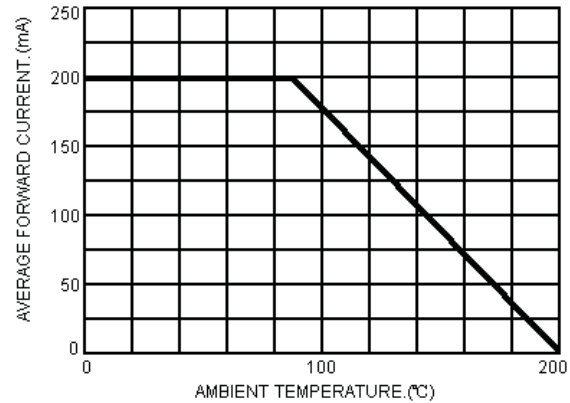


FIG.3-TYPICAL INSTANTANEOUS FORWARD CHARACTERISTICS

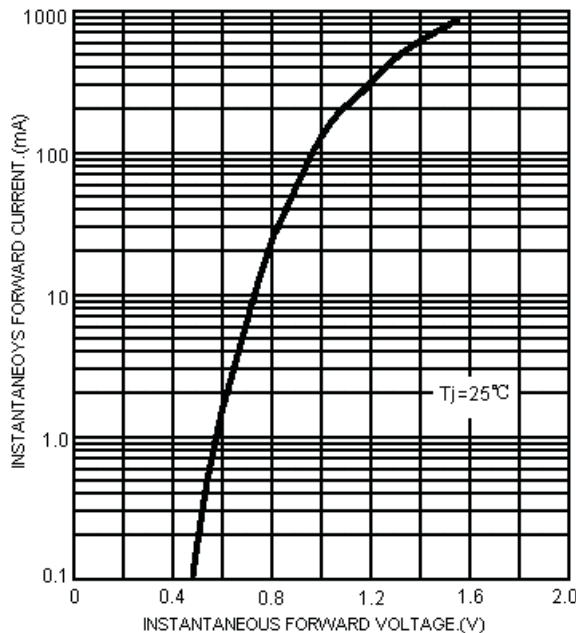


FIG.4-TYPICAL REVERSE CHARACTERISTICS

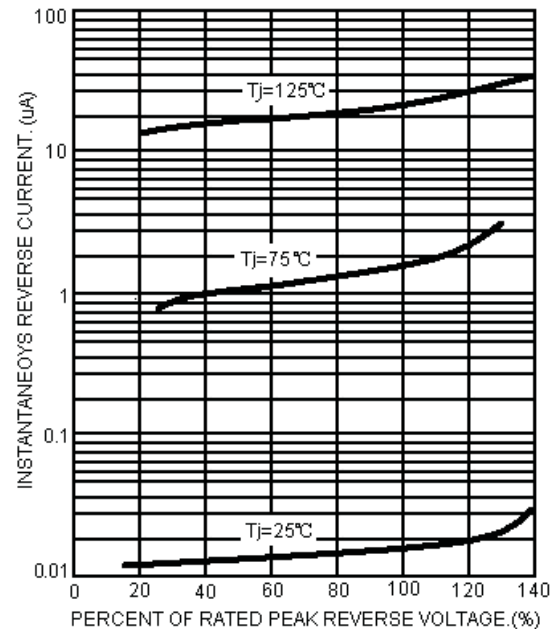


FIG.5-REVERSE RECOVER TIME CHARACTERISTIC AND TEST CIRCUIT DIAGRAM

